

IRG7PSH50UDPbF

INSULATED GATE BIPOLAR TRANSISTOR WITH ULTRAFAST SOFT RECOVERY DIODE

Features

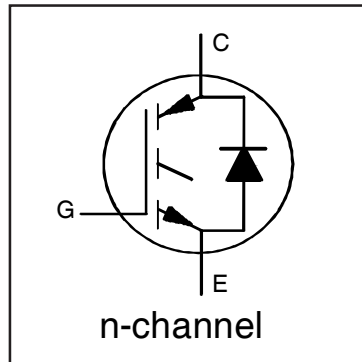
- Low $V_{CE(ON)}$ trench IGBT technology
- Low switching losses
- Square RBSOA
- 100% of the parts tested for I_{LM} ①
- Positive $V_{CE(ON)}$ temperature co-efficient
- Ultra fast soft recovery co-pak diode
- Tight parameter distribution
- Lead-Free

Benefits

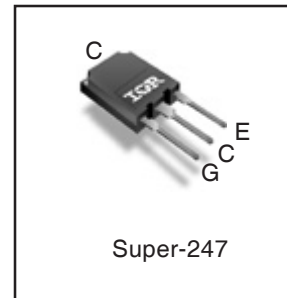
- High efficiency in a wide range of applications
- Suitable for a wide range of switching frequencies due to low $V_{CE(ON)}$ and low switching losses
- Rugged transient performance for increased reliability
- Excellent current sharing in parallel operation

Applications

- U.P.S.
- Welding
- Solar Inverter
- Induction Heating



$V_{CES} = 1200V$
$I_{NOMINAL} = 50A$
$T_{J(max)} = 150^{\circ}C$
$V_{CE(on)} \text{ typ.} = 1.7V$



G	C	E
Gate	Collector	Emitter

Absolute Maximum Ratings

	Parameter	Max.	Units	
V_{CES}	Collector-to-Emitter Voltage	1200	V	
$I_C @ T_C = 25^{\circ}C$	Continuous Collector Current (Silicon Limited)	116	A	
$I_C @ T_C = 100^{\circ}C$	Continuous Collector Current (Silicon Limited)	70		
$I_{NOMINAL}$	Nominal Current	50		
I_{CM}	Pulse Collector Current, $V_{GE} = 15V$	150		
I_{LM}	Clamped Inductive Load Current, $V_{GE} = 20V$ ①	200		
$I_F @ T_C = 25^{\circ}C$	Diode Continuous Forward Current	116		
$I_F @ T_C = 100^{\circ}C$	Diode Continuous Forward Current	70		
I_{FM}	Diode Maximum Forward Current ②	200		
V_{GE}	Continuous Gate-to-Emitter Voltage	± 30		V
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	462		W
$P_D @ T_C = 100^{\circ}C$	Maximum Power Dissipation	185		
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	$^{\circ}C$	
	Soldering Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)		
	Mounting Torque, 6-32 or M3 Screw	10 lbf-in (1.1 N-m)		

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance Junction-to-Case-(each IGBT) ④	—	—	0.27	$^{\circ}C/W$
$R_{\theta JC}$ (Diode)	Thermal Resistance Junction-to-Case-(each Diode) ④	—	—	0.37	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink (flat, greased surface)	—	0.24	—	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (typical socket mount)	—	40	—	

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage	1200	—	—	V	$V_{GE} = 0V, I_C = 100\mu\text{A}$ ③
$\Delta V_{(BR)CES}/\Delta T_J$	Temperature Coeff. of Breakdown Voltage	—	1.0	—	V/°C	$V_{GE} = 0V, I_C = 1.0\text{mA}$ (25°C-150°C)
$V_{CE(on)}$	Collector-to-Emitter Saturation Voltage	—	1.7	2.0	V	$I_C = 50A, V_{GE} = 15V, T_J = 25^\circ\text{C}$
		—	2.0	—		$I_C = 50A, V_{GE} = 15V, T_J = 150^\circ\text{C}$
$V_{GE(th)}$	Gate Threshold Voltage	3.0	—	6.0	V	$V_{CE} = V_{GE}, I_C = 2.0\text{mA}$
$\Delta V_{GE(th)}/\Delta T_J$	Threshold Voltage temp. coefficient	—	-17	—	mV/°C	$V_{CE} = V_{GE}, I_C = 1.0\text{mA}$ (25°C - 150°C)
g_{fe}	Forward Transconductance	—	55	—	S	$V_{CE} = 50V, I_C = 50A, PW = 30\mu\text{s}$
I_{CES}	Collector-to-Emitter Leakage Current	—	2.0	100	μA	$V_{GE} = 0V, V_{CE} = 1200V$
		—	3700	—		$V_{GE} = 0V, V_{CE} = 1200V, T_J = 150^\circ\text{C}$
V_{FM}	Diode Forward Voltage Drop	—	3.0	3.9	V	$I_F = 50A$
		—	2.7	—		$I_F = 50A, T_J = 150^\circ\text{C}$
I_{GES}	Gate-to-Emitter Leakage Current	—	—	± 200	nA	$V_{GE} = \pm 30V$

Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
Q_g	Total Gate Charge (turn-on)	—	290	440	nC	$I_C = 50A$ $V_{GE} = 15V$ $V_{CC} = 600V$
Q_{ge}	Gate-to-Emitter Charge (turn-on)	—	40	60		
Q_{gc}	Gate-to-Collector Charge (turn-on)	—	110	170		
E_{on}	Turn-On Switching Loss	—	3600	4600	μJ	$I_C = 50A, V_{CC} = 600V, V_{GE} = 15V$ $R_G = 5.0\Omega, L = 200\mu\text{H}, T_J = 25^\circ\text{C}$ Energy losses include tail & diode reverse recovery
E_{off}	Turn-Off Switching Loss	—	2200	3200		
E_{total}	Total Switching Loss	—	5800	7800		
$t_{d(on)}$	Turn-On delay time	—	35	55	ns	
t_r	Rise time	—	40	60		
$t_{d(off)}$	Turn-Off delay time	—	430	500		
t_f	Fall time	—	45	65		
t_{off}	Turn-Off delay time	—	480	—		
E_{on}	Turn-On Switching Loss	—	5080	—	μJ	$I_C = 50A, V_{CC} = 600V, V_{GE} = 15V$ $R_G = 5.0\Omega, L = 200\mu\text{H}, T_J = 150^\circ\text{C}$ ③ Energy losses include tail & diode reverse recovery
E_{off}	Turn-Off Switching Loss	—	3370	—		
E_{total}	Total Switching Loss	—	8450	—		
$t_{d(on)}$	Turn-On delay time	—	30	—	ns	
t_r	Rise time	—	40	—		
$t_{d(off)}$	Turn-Off delay time	—	480	—		
t_f	Fall time	—	170	—		
C_{ies}	Input Capacitance	—	6000	—	pF	$V_{GE} = 0V$ $V_{CC} = 30V$ $f = 1.0\text{Mhz}$
C_{oes}	Output Capacitance	—	300	—		
C_{res}	Reverse Transfer Capacitance	—	130	—		
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE				$T_J = 150^\circ\text{C}, I_C = 200A$ $V_{CC} = 960V, V_p = 1200V$ $R_g = 5.0\Omega, V_{GE} = +20V \text{ to } 0V$
E_{rec}	Reverse Recovery Energy of the Diode	—	1510	—	μJ	$T_J = 150^\circ\text{C}$
t_{rr}	Diode Reverse Recovery Time	—	190	—	ns	$V_{CC} = 600V, I_F = 5.0A$
I_{rr}	Peak Reverse Recovery Current	—	5760	—	A	$R_g = 5.0\Omega, L = 1.0\text{mH}$

Notes:

- ① $V_{CC} = 80\% (V_{CES}), V_{GE} = 20V, L = 200\mu\text{H}, R_G = 5.0\Omega$.
- ② Pulse width limited by max. junction temperature.
- ③ Refer to AN-1086 for guidelines for measuring $V_{(BR)CES}$ safely.
- ④ R_θ is measured at T_J of approximately 90°C .

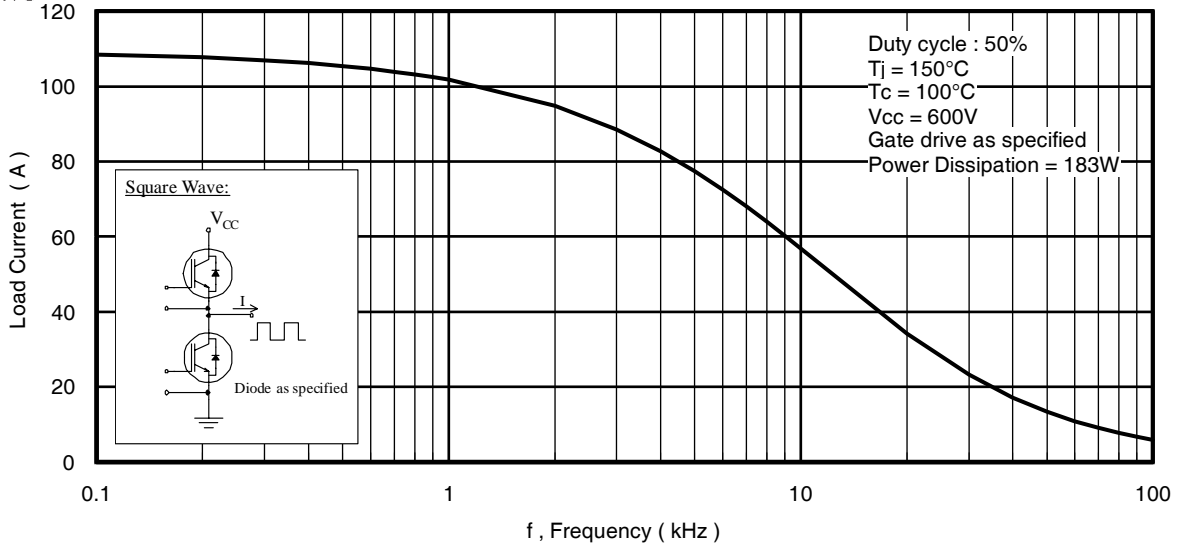


Fig. 1 - Typical Load Current vs. Frequency
(Load Current = I_{RMS} of fundamental)

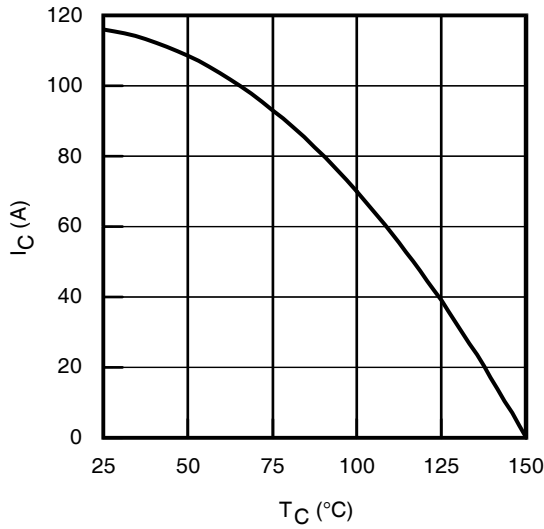


Fig. 1 - Maximum DC Collector Current vs. Case Temperature

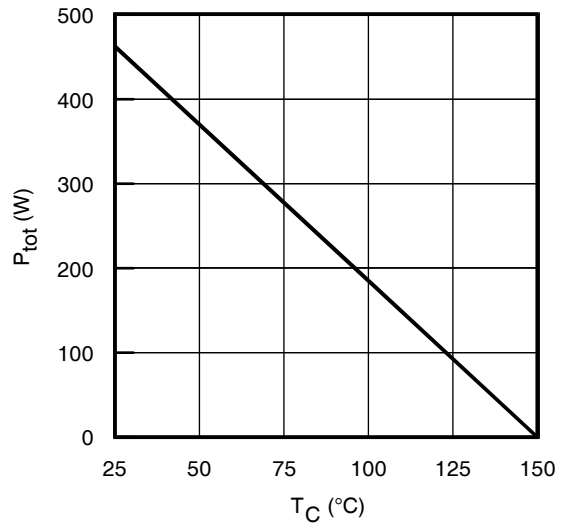


Fig. 2 - Power Dissipation vs. Case Temperature

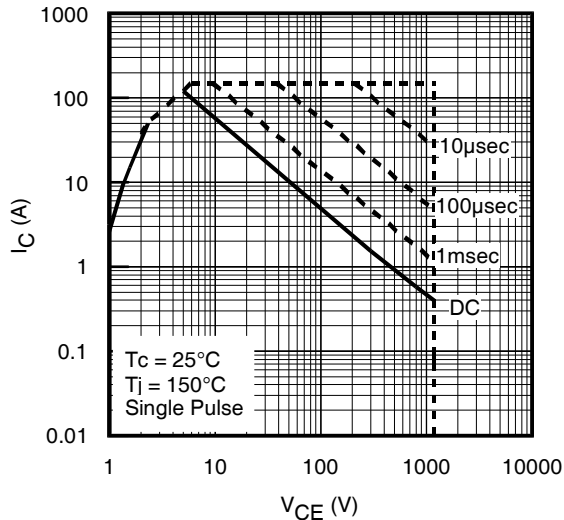


Fig. 3 - Forward SOA
 $T_C = 25^\circ\text{C}$, $T_J \leq 150^\circ\text{C}$; $V_{GE} = 15\text{V}$

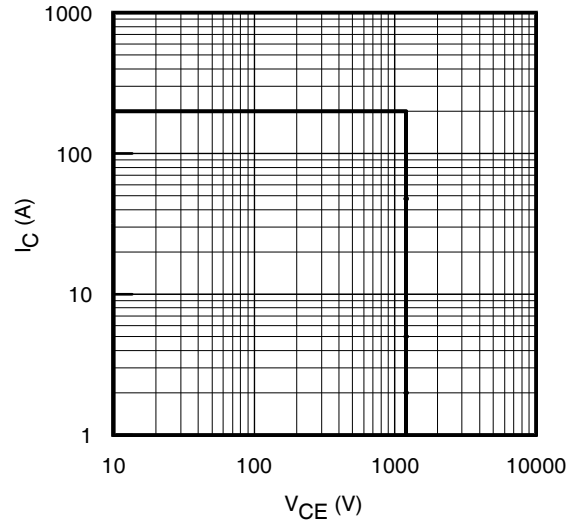


Fig. 4 - Reverse Bias SOA
 $T_J = 150^\circ\text{C}$; $V_{GE} = 20\text{V}$

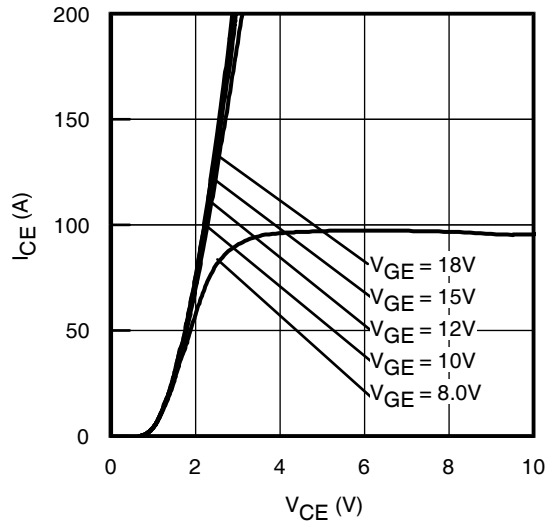


Fig. 5 - Typ. IGBT Output Characteristics
 $T_J = -40^\circ\text{C}$; $t_p = 30\mu\text{s}$

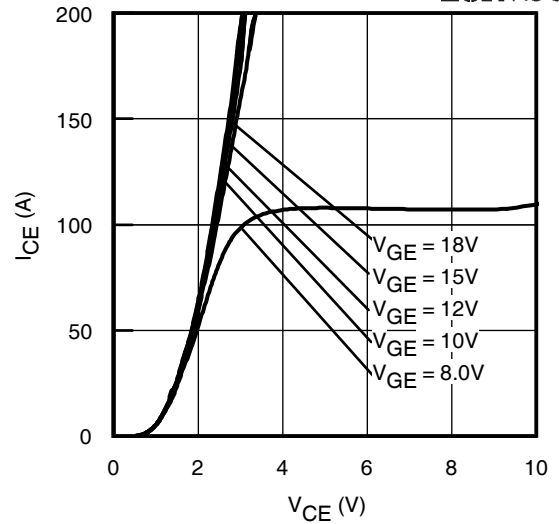


Fig. 6 - Typ. IGBT Output Characteristics
 $T_J = 25^\circ\text{C}$; $t_p = 30\mu\text{s}$

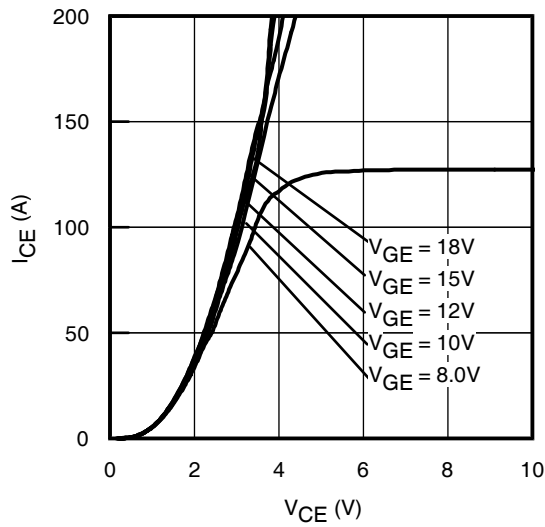


Fig. 7 - Typ. IGBT Output Characteristics
 $T_J = 150^\circ\text{C}$; $t_p = 30\mu\text{s}$

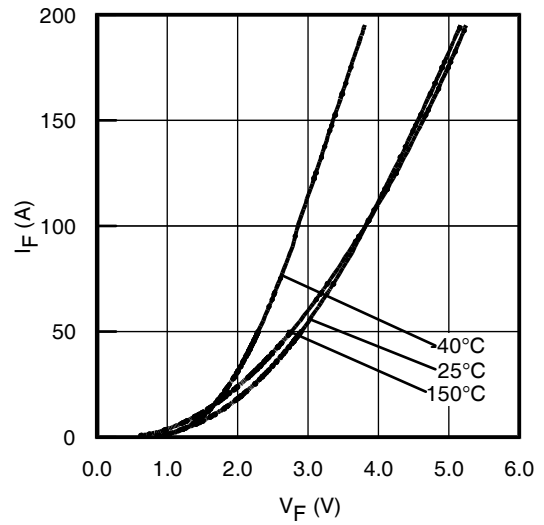


Fig. 8 - Typ. Diode Forward Characteristics
 $t_p = 30\mu\text{s}$

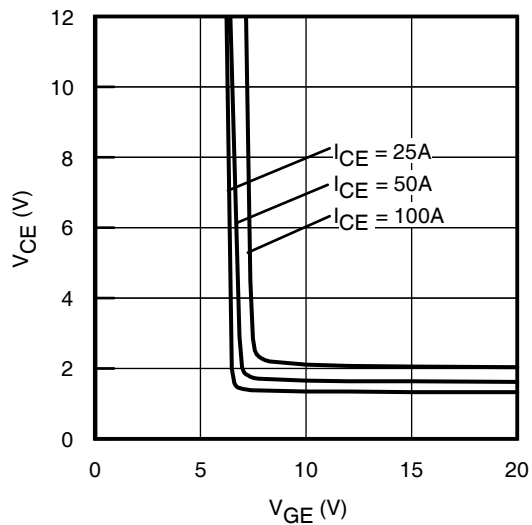


Fig. 9 - Typical V_{CE} vs. V_{GE}
 $T_J = -40^\circ\text{C}$

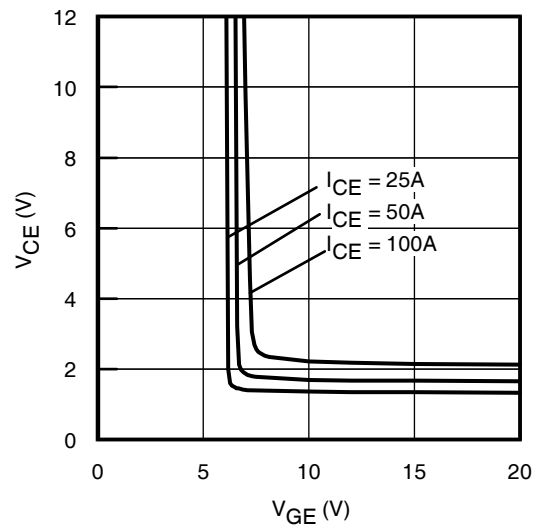


Fig. 10 - Typical V_{CE} vs. V_{GE}
 $T_J = 25^\circ\text{C}$

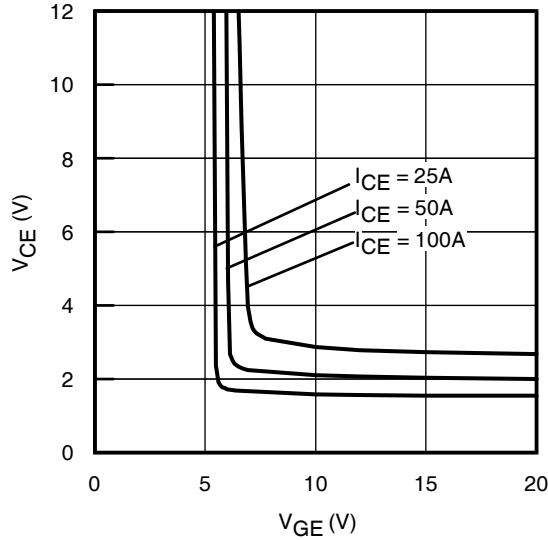


Fig. 11 - Typical V_{CE} vs. V_{GE}
 $T_J = 150^\circ\text{C}$

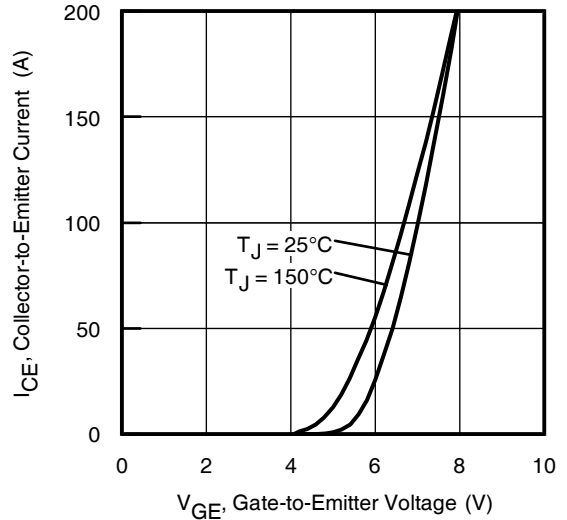


Fig. 12 - Typ. Transfer Characteristics
 $V_{CE} = 50\text{V}$; $t_p = 30\mu\text{s}$

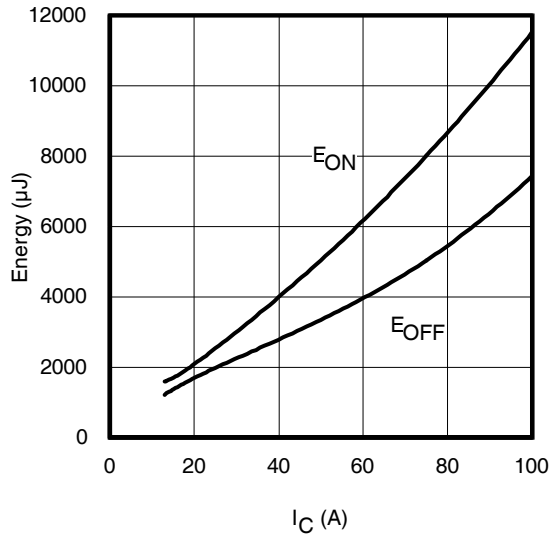


Fig. 13 - Typ. Energy Loss vs. I_C
 $T_J = 150^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 600\text{V}$, $R_G = 5.0\Omega$; $V_{GE} = 15\text{V}$

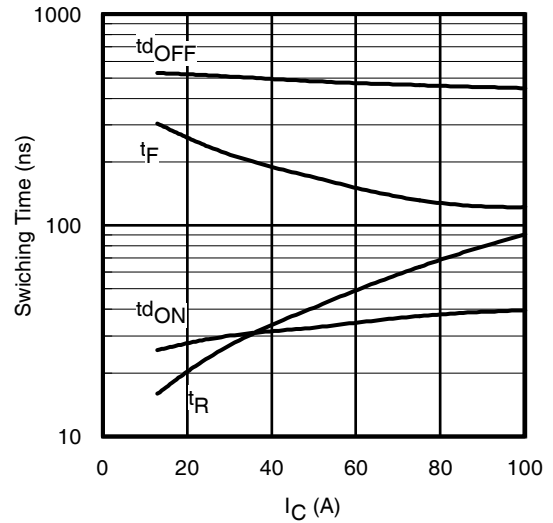


Fig. 14 - Typ. Switching Time vs. I_C
 $T_J = 150^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 600\text{V}$, $R_G = 5.0\Omega$; $V_{GE} = 15\text{V}$

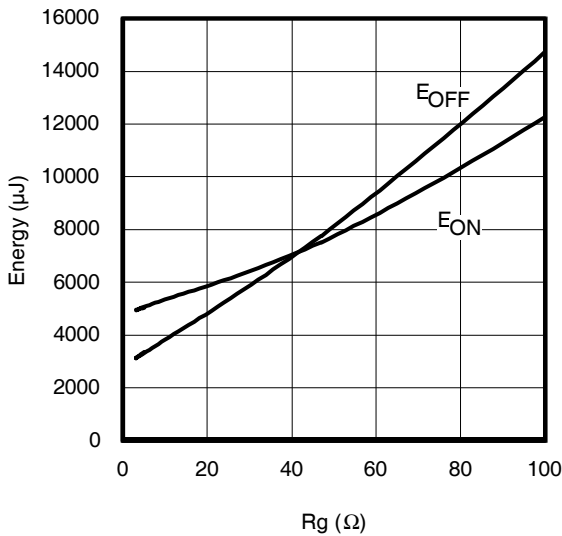


Fig. 15 - Typ. Energy Loss vs. R_G
 $T_J = 150^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 600\text{V}$, $I_{CE} = 50\text{A}$; $V_{GE} = 15\text{V}$

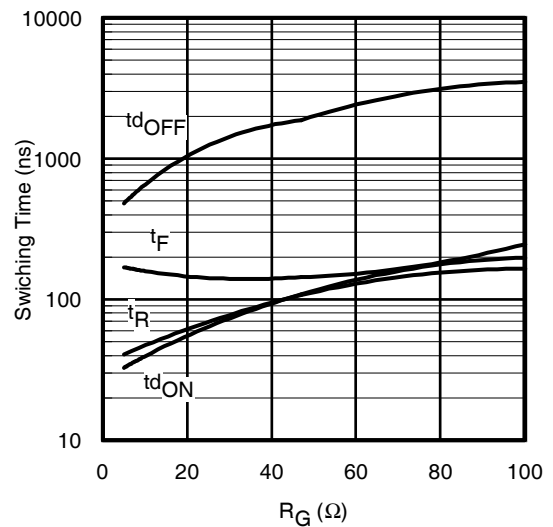


Fig. 16 - Typ. Switching Time vs. R_G
 $T_J = 150^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 600\text{V}$, $I_{CE} = 50\text{A}$; $V_{GE} = 15\text{V}$

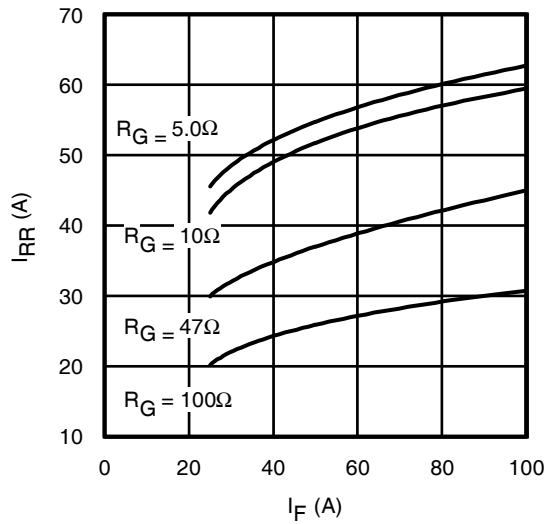


Fig. 17 - Typ. Diode I_{RR} vs. I_F
 $T_J = 150^\circ\text{C}$

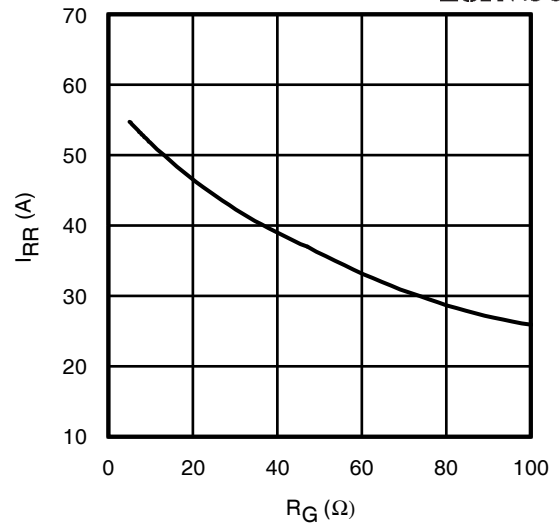


Fig. 18 - Typ. Diode I_{RR} vs. R_G
 $T_J = 150^\circ\text{C}$

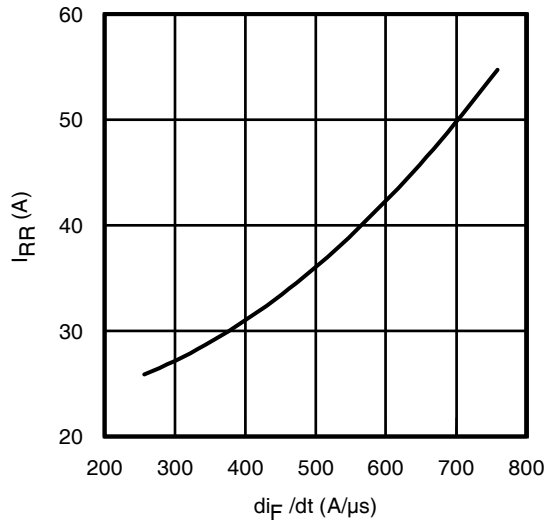


Fig. 19 - Typ. Diode I_{RR} vs. di_F/dt
 $V_{CC} = 600\text{V}; V_{GE} = 15\text{V}; I_F = 50\text{A}; T_J = 150^\circ\text{C}$

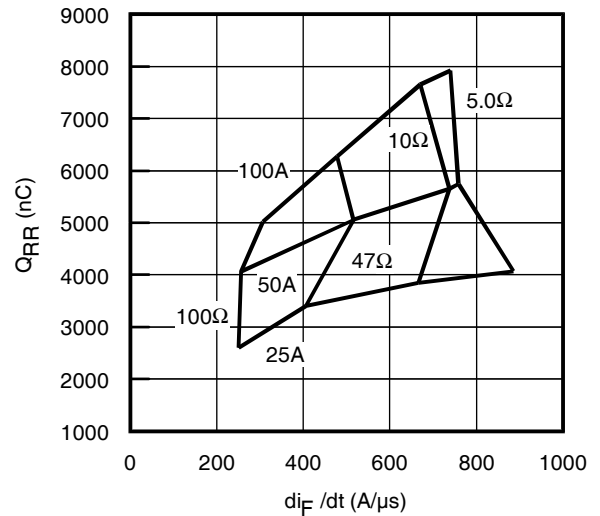


Fig. 20 - Typ. Diode Q_{RR} vs. di_F/dt
 $V_{CC} = 600\text{V}; V_{GE} = 15\text{V}; T_J = 150^\circ\text{C}$

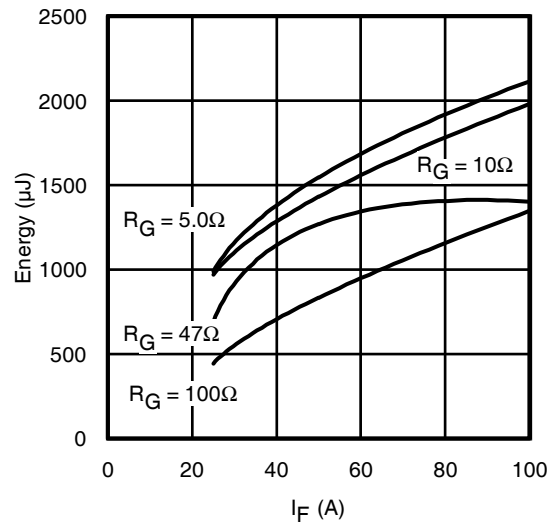


Fig. 21 - Typ. Diode E_{RR} vs. I_F
 $T_J = 150^\circ\text{C}$

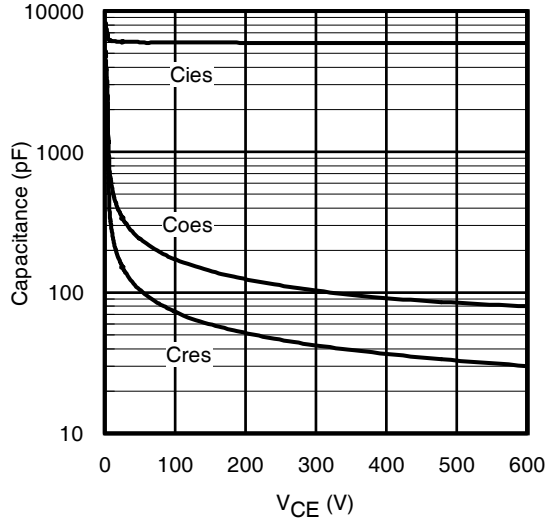


Fig. 22 - Typ. Capacitance vs. V_{CE}
V_{GE} = 0V; f = 1MHz

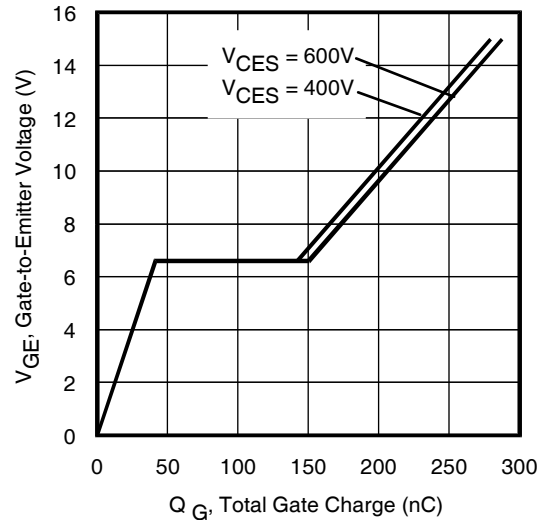


Fig. 23 - Typical Gate Charge vs. V_{GE}
I_{CE} = 50A

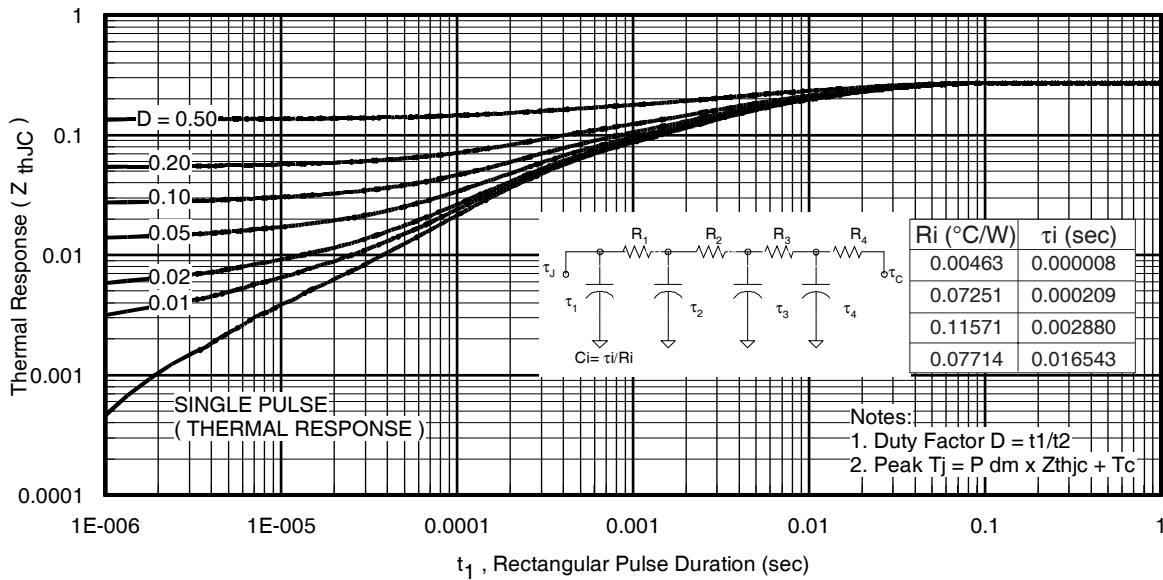


Fig. 24. Maximum Transient Thermal Impedance, Junction-to-Case (IGBT)

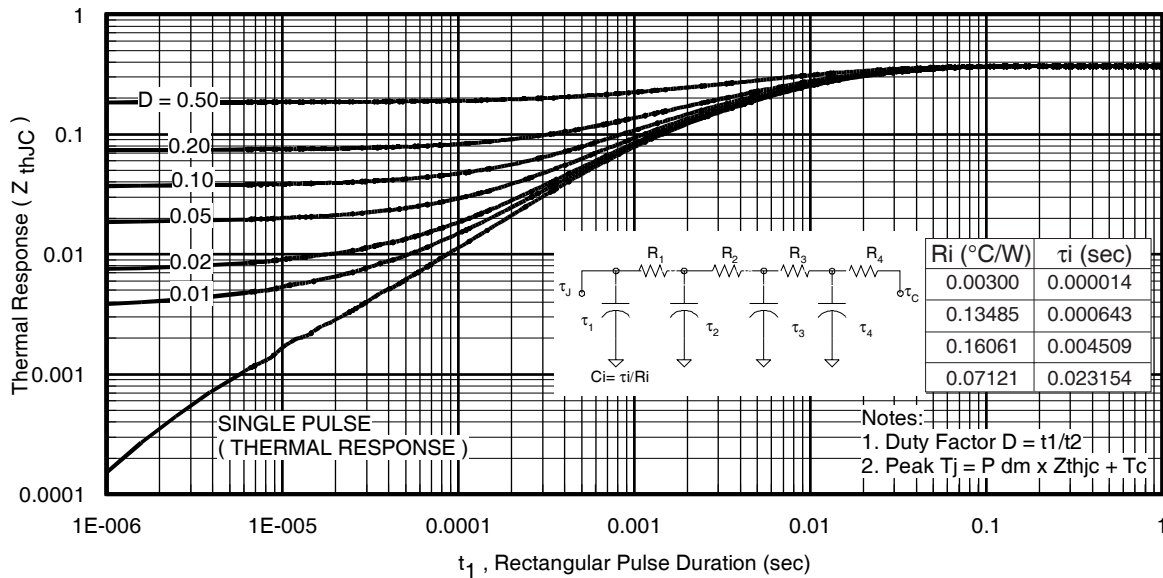


Fig. 25. Maximum Transient Thermal Impedance, Junction-to-Case (DIODE)

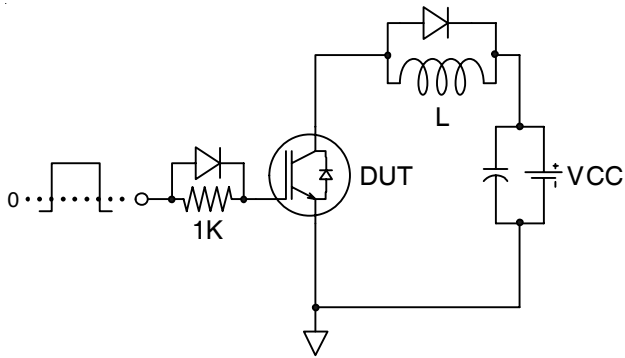


Fig.C.T.1 - Gate Charge Circuit (turn-off)

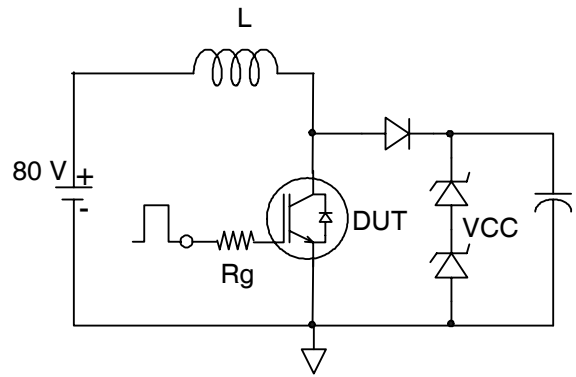


Fig.C.T.2 - RBSOA Circuit

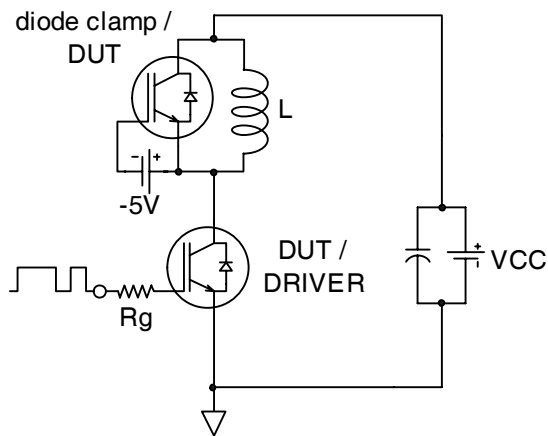


Fig.C.T.3 - Switching Loss Circuit

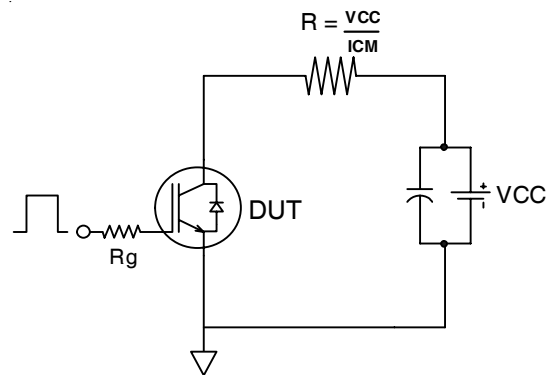


Fig.C.T.4 - Resistive Load Circuit

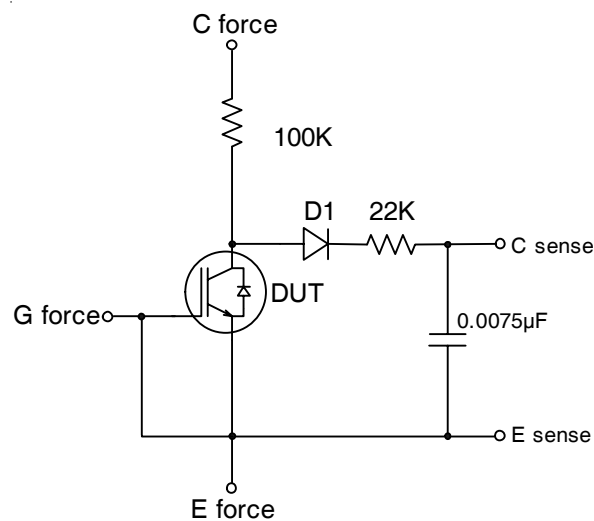


Fig.C.T.5 - BVCES Filter Circuit

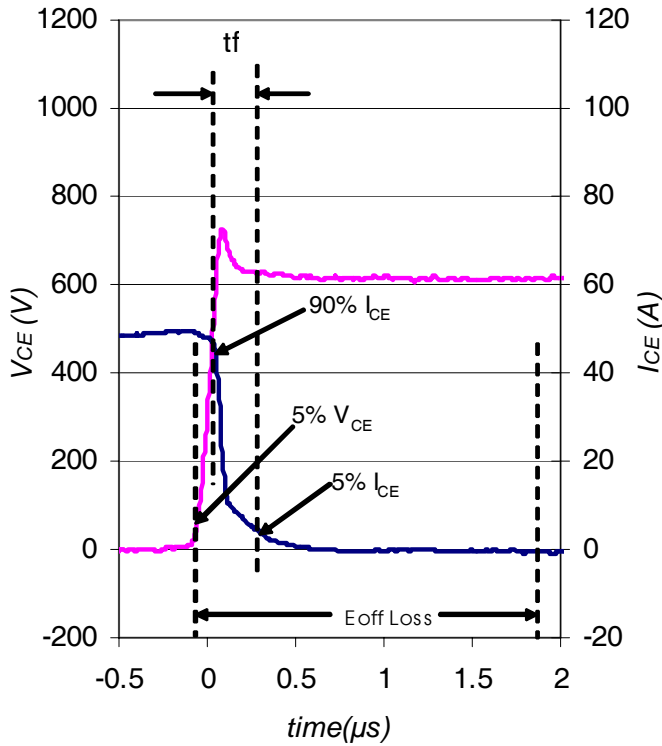


Fig. WF1 - Typ. Turn-off Loss Waveform
@ $T_J = 150^\circ\text{C}$ using Fig. CT.4

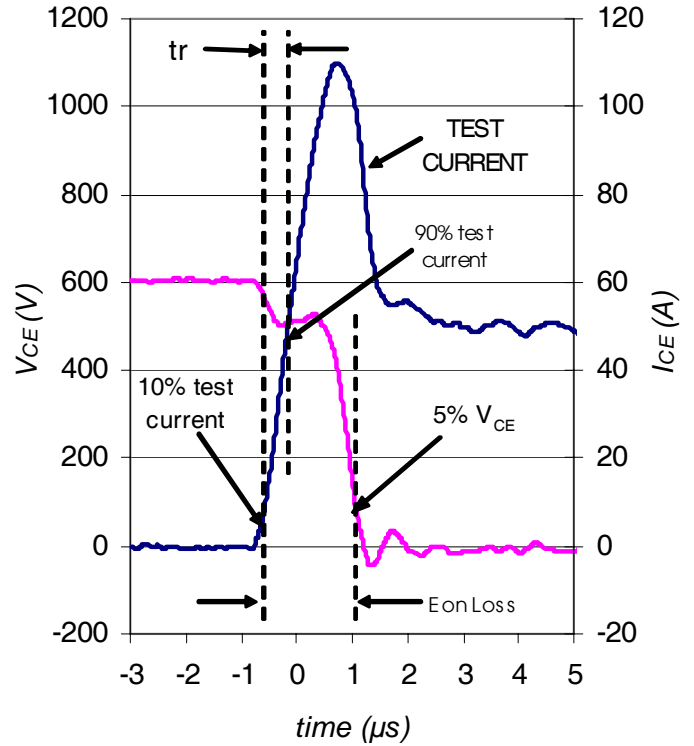


Fig. WF2 - Typ. Turn-on Loss Waveform
@ $T_J = 150^\circ\text{C}$ using Fig. CT.4

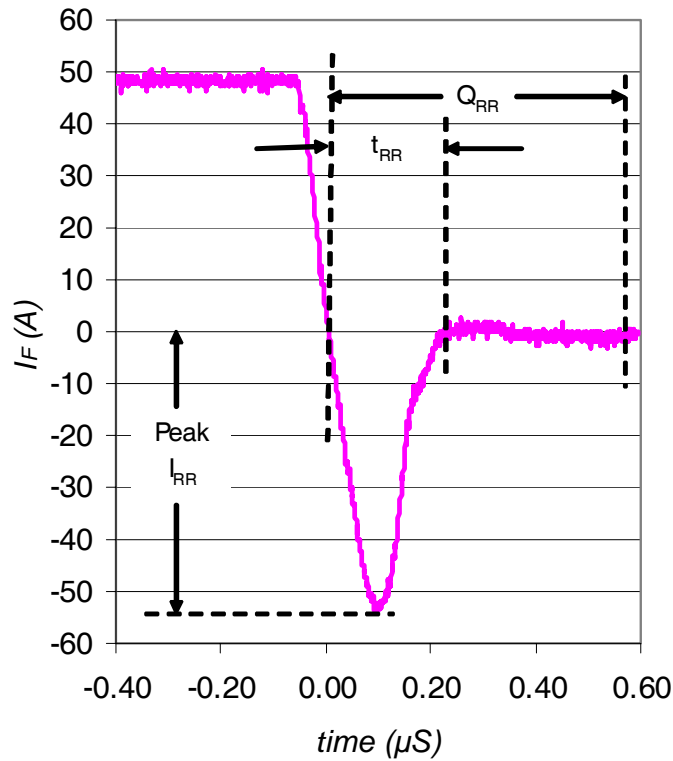


Fig. WF3 - Typ. Diode Recovery Waveform
@ $T_J = 150^\circ\text{C}$ using Fig. CT.4

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